

Title (en)

FILTER SUBSTRATE FOR FILTERING AND OPTICALLY CHARACTERIZING MICROPARTICLES, METHOD FOR PRODUCING THE FILTER SUBSTRATE, AND USE OF THE FILTER SUBSTRATE

Title (de)

FILTERSUBSTRAT ZUR FILTERUNG UND OPTISCHEN CHARAKTERISIERUNG VON MIKROPARTIKELN. VERFAHREN ZUR HERSTELLUNG DES FILTERSUBSTRATS UND VERWENDUNG DES FILTERSUBSTRATS

Title (fr)

SUBSTRAT FILTRANT POUR FILTRER ET EFFECTUER LA CARACTÉRISATION OPTIQUE DE MICROPARTICULES PROCÉDÉ DE FABRICATION DUDIT SUBSTRAT FILTRANT ET UTILISATION DU SUBSTRAT FILTRANT

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Application

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Abstract (en)

[origin: WO2019197542A1] The present invention relates to a filter substrate for filtering and optically characterizing microparticles. The filter substrate comprises a wafer having a thickness of at least 100 pm and a transmittance of at least 10% for radiation in the wavelength range of 2500 nm to 15000 nm. Furthermore, the surface of the front side and/or the surface of the rear side of the wafer is completely or partially provided with an antireflective layer, which prevents the optical reflection of radiation in the wavelength range of 200 nm to 10000 nm. Moreover, the wafer has, at least in some regions, filter holes having a diameter of 1 pm to 5 mm. With the filter substrate according to the invention, microparticles can be filtered and the microparticles on the filter substrate can be subsequently optically characterized with very high measurement quality. The present invention further relates to a method for producing the filter substrate according to the invention and to the use of the filter substrate according to the invention.

IPC 8 full level

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